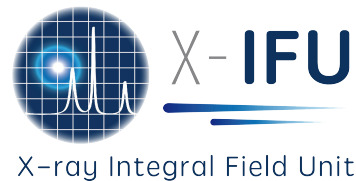

TES-Simulations

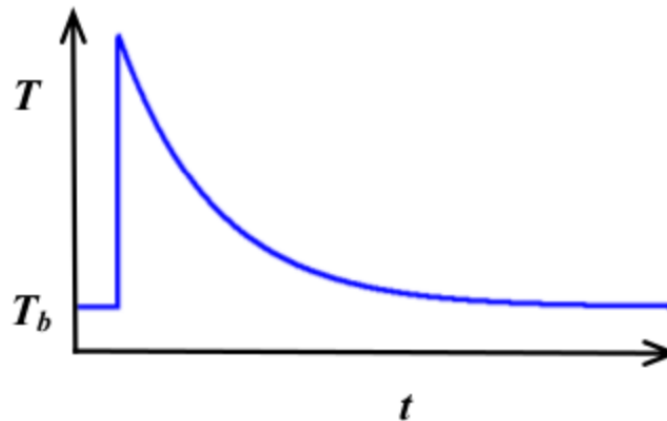
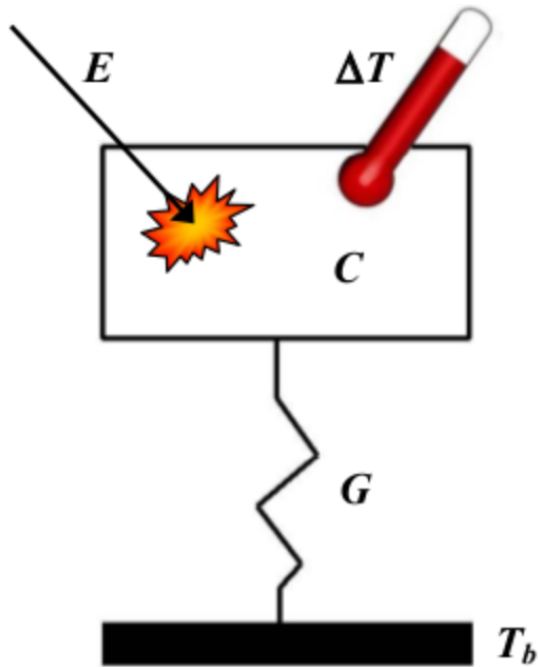
Jörn Wilms (ECAP), P. Peille (IRAP), C. Kirsch (ECAP), M. Lorenz (ECAP),
M. Ceballos (IFCA), T. Dauser (ECAP), P. Merino (UA), S.J. Smith (GSFC),
B. Cobo (IFCA), S. Bandler (GSFC), R. den Hartog (SRON), J. de Plaa (SRON),
E. Pointecouteau (IRAP), D. Barret (IRAP)



X-IFU photon detection process:

- sensitivity described by effective area curves
(taking into account mirror reflectivity, pixel sensitivity, gaps)
- Two (input/output-compatible) simulation approaches
 - **xifupipeline**:
 - * full imaging implemented
 - * fast detection simulation using response matrices
 - ⇒ Well suited for faint sources
 - **tessim/sirena**
 - * Simulation of TES physics and pulse reconstruction
 - * Slower than xifupipeline, but much better physics
 - ⇒ Well suited for bright sources
 - ⇒ Well suited for engineering studies

Device Simulations: Principle



Smith (2006 PhD Leicester)

Calorimeter: measure temperature change in **device** with temperature T_0 connected to **heat bath** with temperature T_S .

Joule heating by current through device $\implies T_0 > T_S$

Absorption: temperature rises: $\Delta T = E_\gamma / C$

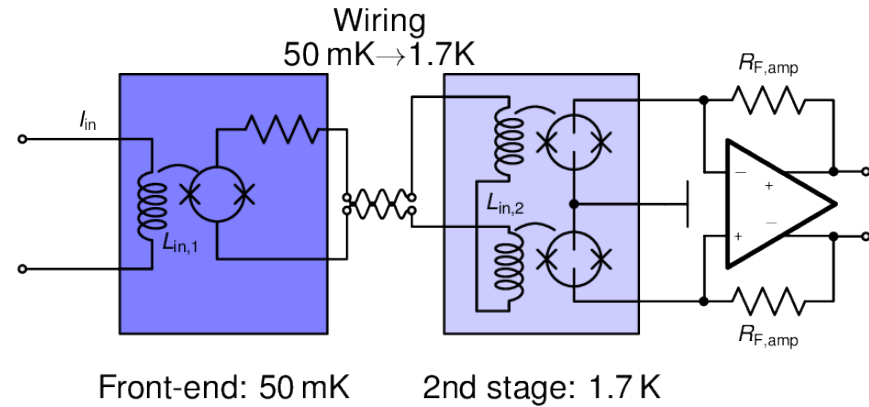
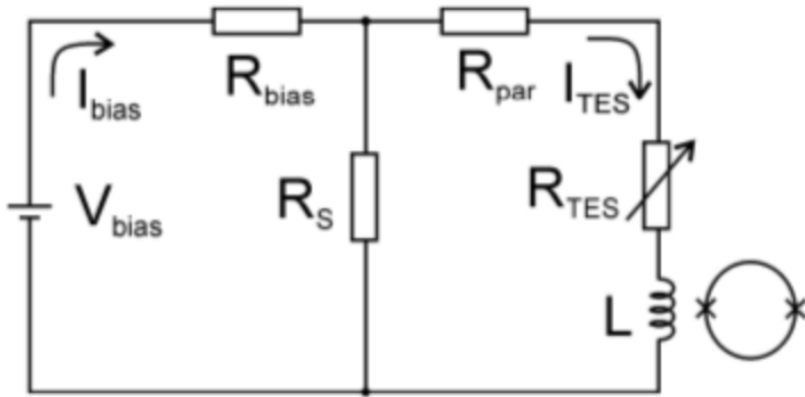
C : heat capacity

Relaxes back to T_0 . Typical timescale: $\tau = C / G$.

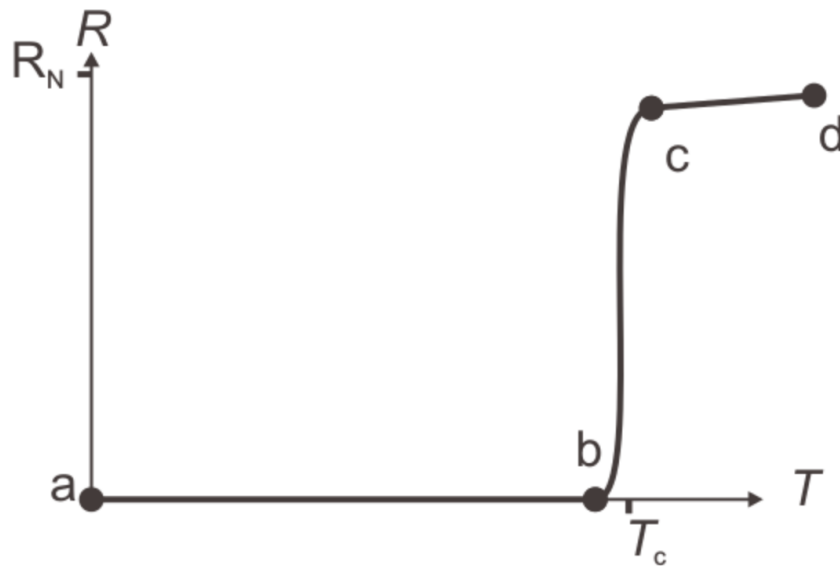
Resolution given by thermal fluctuations: $\Delta E = 2.35\sqrt{kT^2C}$

\implies Small (**few eV**) for T small (mK)

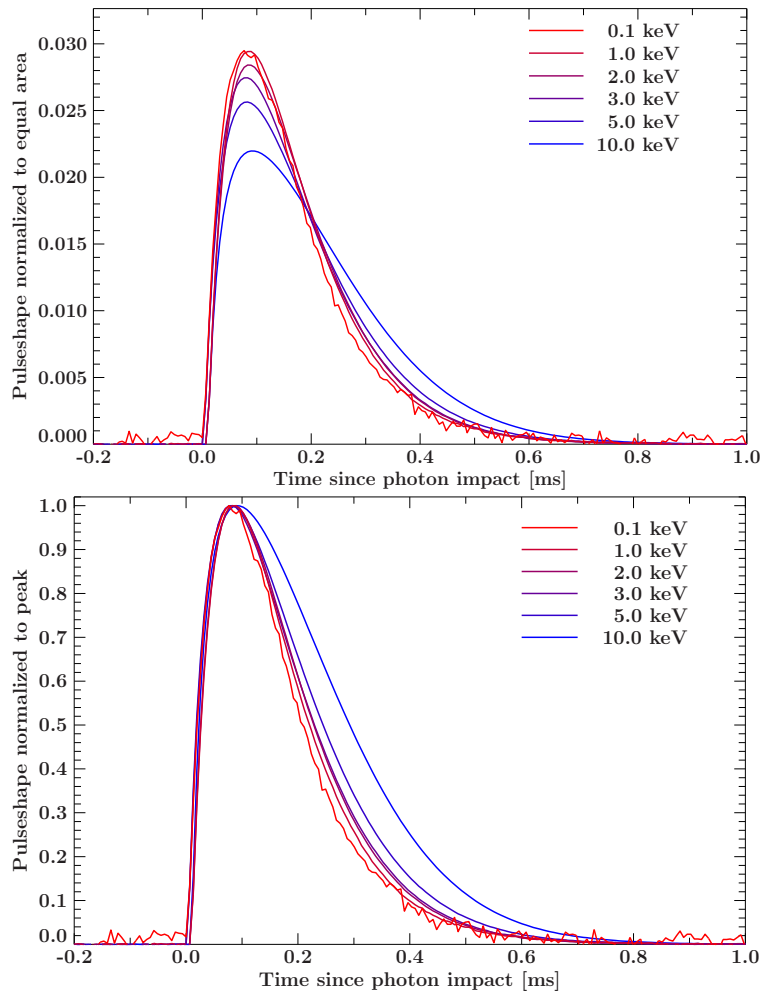
Device Simulations: Principle



Kinnunen (2011, PhD Jyväskylä)



negative electrothermal feedback: Operate circuit at **Transition Edge** between superconduction and normal conduction,
voltage bias circuit:
 absorption $\implies R \nearrow$
 \implies Joule power $P_J = I^2 R \searrow$
 \implies faster cooling than for $R = \text{const}$
 Typical time constants $75 \mu\text{s} \dots 400 \mu\text{s}$



Typical pulse shapes for 0.1, 1, 2, 3, 5, 10 keV, normalized to top: equal area, bottom: peak current.

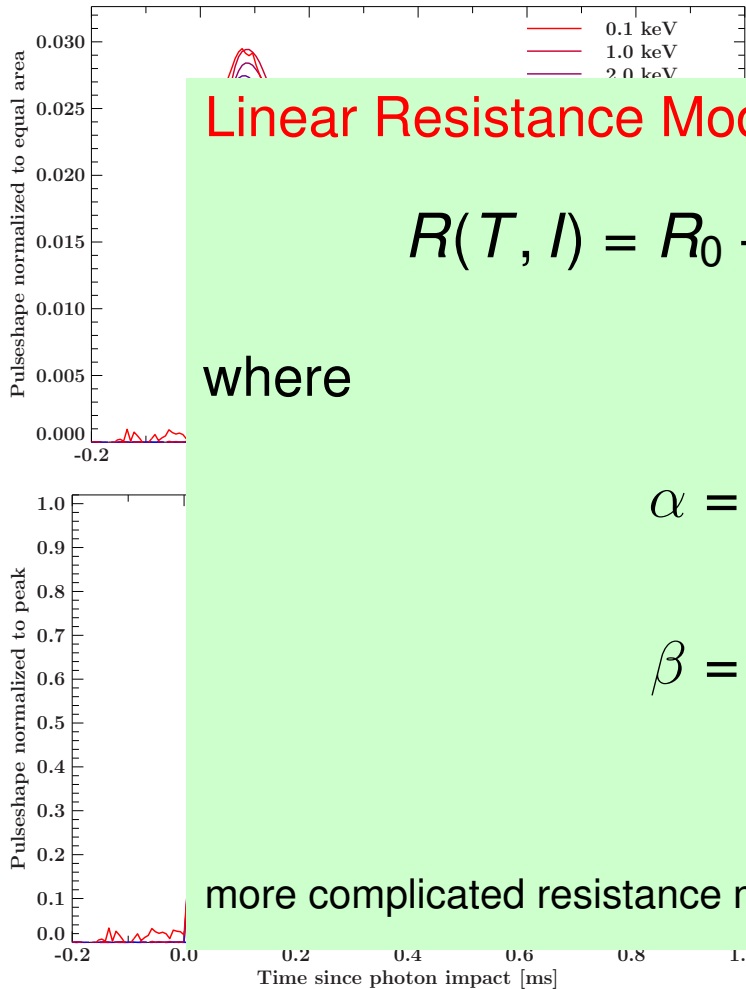
- based on GSFC code by S.J. Smith
- numerical solution of differential equations for $T(t)$, $I(t)$ (e.g., Irwin & Hilton, 2005),

$$C \frac{dT}{dt} = -P_b + P_J + P + \text{Noise}$$

$$L \frac{dI}{dt} = V - IR_L - IR(T, I) + \text{Noise}$$

- linear resistance model, $R(T, I; \alpha, \beta)$
- noise treatment: Johnson of circuit, bath, excess noise
- input parameters: C , G_b , n , α , β , m , R_0 , T_0 , T_b , L_{crit}

including flexible, FITS-based library of pixel types



Linear Resistance Model:

$$R(T, I) = R_0 + \left. \frac{\partial R}{\partial T} \right|_{I_0} (T - T_0) + \left. \frac{\partial R}{\partial I} \right|_{T_0} (I - I_0) \quad (1)$$

where

$$\alpha = \left. \frac{\partial \log R}{\partial \log T} \right|_{I_0} = \frac{T_0}{R_0} \left. \frac{\partial R}{\partial T} \right|_{I_0} \quad (2)$$

$$\beta = \left. \frac{\partial \log R}{\partial \log I} \right|_{T_0} = \frac{I_0}{R_0} \left. \frac{\partial R}{\partial I} \right|_{T_0} \quad (3)$$

more complicated resistance models also exist (“cross talk”)

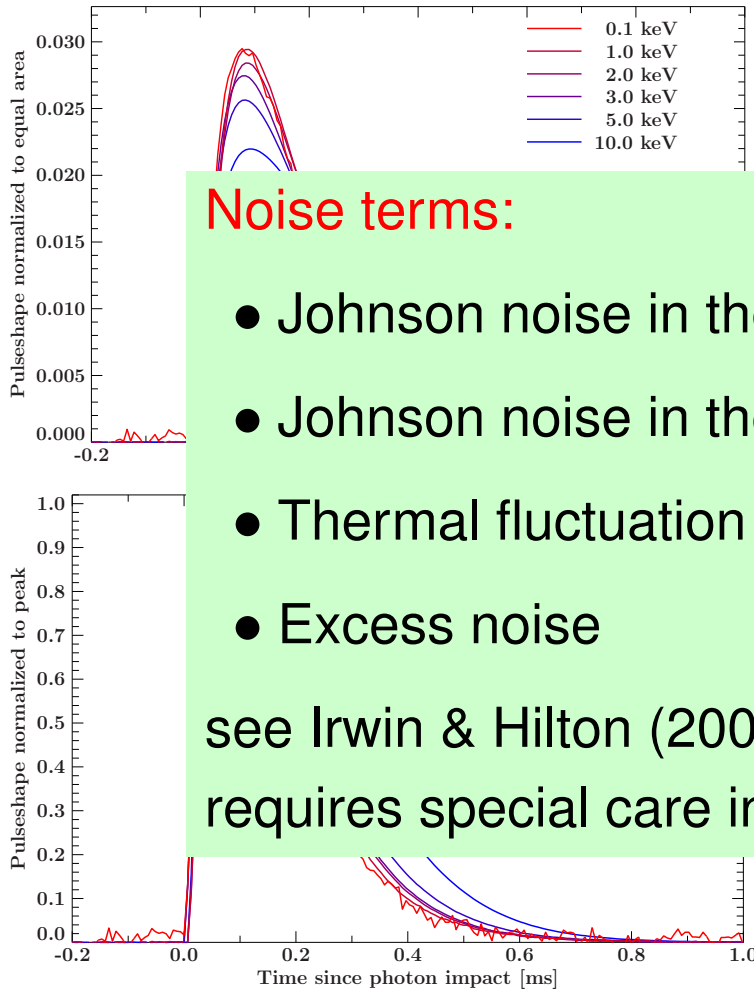
Typical pulse shapes for 0.1, 1, 2, 3, 5, 10 keV, normalized to top: equal area, bottom: peak current.

- input parameters: $C, G_b, n, \alpha, \beta, m, R_0, T_0, T_b, L_{crit}$

including flexible, FITS-based library of pixel types

h
qua-
lton,

noise
, β)
t, bath,



Noise terms:

- Johnson noise in the TES
- Johnson noise in the load resistor
- Thermal fluctuation noise
- Excess noise

see Irwin & Hilton (2005) for details

requires special care in numerical integrator

Typical pulse shapes for 0.1, 1, 2, 3, 5, 10 keV, normalized to top: equal area, bottom: peak current.

- based on GSFC code by S.J. Smith

- noise treatment: Johnson of circuit, bath, excess noise

- input parameters: C , G_b , n , α , β , m , R_0 , T_0 , T_b , L_{crit}

including flexible, FITS-based library of pixel types

qua-
lton,

Noise

, β)

noise treatment: Johnson of circuit, bath,

Parameter	IXO baseline	DM	LPA	SPA
Pixel size	249 μm	249 μm	249 - 300 μm	75 - 110 μm
Heat capacity, C @ T_0	0.8 pJ/K	0.8 pJ/K	0.8 pJ/K	0.26 pJ/K
Bath conductance, G_b @ T_0	200 pW/K	115 pW/K	57 pW/K	300 pW/K
Temperature exponent, n	3.0	3.0	3.0	4.0
α	75	75	75	100
β	1.25	1.25	1.25	10
Unexplained noise factor, M	0	0	0	0.8
Resistance, R_0	1 m Ω	1 m Ω	1 m Ω	1.1 m Ω
Current, I_0	69.5 μA	52.5 μA	37.1 μA	73.5 μA
Temperature, T_0	90 mK	90 mK	90 mK	90 mK
Power, P_0	4.81 pW	2.76 pW	1.38 pW	5.95 pW
R_{shunt}^*	49 $\mu\Omega$	90 $\mu\Omega$	207 $\mu\Omega$	91 $\mu\Omega$
Transformer Turns Ratio *	5.53	4.08	2.69	4.05
L_{crit}	66 nH	120 nH	276 nH	122 nH
τ_{eff}	431 μs	0.795 ms	1.87 ms	305 μs
τ_{crit}	156 μs	286 μs	649 μs	78 μs
Time constraint for 80% high res.	8.6 ms	112 ms	112 ms	4 ms
ΔE_{FWHM} (∞ rec length, small signal)	1.69 eV	1.70 eV	1.73 eV	1.54 eV
ΔE_{FWHM} (high res, small signal)	1.83 eV	1.71 eV	1.76 eV	1.69 eV
Max slew rate / keV	88 mA/s/keV	36 mA/s/keV	11 mA/s/keV	229 mA/s/keV
f_{eff} - effective / information bandwidth	970 Hz	560 Hz	280 Hz	1710 Hz

Source: Steve Smith, GSFC, 29-05-2015

* Assumes 1.5 m Ω parasitic from capacitive element, and filter L = 2 μH , $T_{\text{shunt}} = 70\text{mK}$

Parameter	IXO baseline	DM	LPA	SPA
Pixel size	249 μm	249 μm	249 - 300 μm	75 - 110 μm
Heat capacity, C @ T_0	0.8 pJ/K	0.8 pJ/K	0.8 pJ/K	0.26 pJ/K
Bath conductance, G_b @ T_0	200 pW/K	115 pW/K	57 pW/K	300 pW/K
Temperature exponent, n	3.0	3.0	3.0	4.0
α	75	75	75	100
β	1.25	1.25	1.25	10
Unexplained noise factor, M	0	0	0	0.8
Resistance, R_0	1 m Ω	1 m Ω	1 m Ω	1.1 m Ω
Current, I_0	40.5 μA	50.5 μA	37.1 μA	73.5 μA
Temperature, T_0			90 mK	90 mK
Power, P_0			1.38 pW	5.95 pW
R_{shunt}^*			207 $\mu\Omega$	91 $\mu\Omega$
Transformer Turns Ratio *			2.69	4.05
L_{crit}			276 nH	122 nH
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Max slew rate / keV	88 mA/s/keV	36 mA/s/keV	11 mA/s/keV	229 mA/s/keV
f_{eff} - effective / information bandwidth	970 Hz	560 Hz	280 Hz	1710 Hz

Note: Parameters are outdated!

Source: Steve Smith, GSFC, 29-05-2015

* Assumes 1.5 m Ω parasitic from capacitive element, and filter L = 2 μH , $T_{\text{shunt}} = 70\text{mK}$

Translation to program: (too) many parameters ;-)

```

Parameters for /home/wilms/pfiles/tessim.par
  PixType = SPA           Pixel type
  PixID = 1              Number of pixel
  PixImplist = test_slow.fits  File name of pixel impact list
  Streamfile = stream.fits  File name of output FITS stream
  (tstart = 0.)          Start time of simulation [s]
  (tstop = 1.)           Stop time of simulation [s]
  (sample_rate = 156.25e3)  Sample rate [Hz]
  (acbias = y)           AC biased (yes) or DC biased (no)
  (T_start = 90.0)       Initial operating temperature [mK]
  (Ce = 0.26)            Heat capacity [pJ/K]
  (Gb = 300)             Bath conductance [pW/K]
  (n = 4.0)              Temperature exponent
  (alpha = 100.)         TES sensitivity alpha (T/R*dR/dT)
  (beta = 10.)           TES current dependence beta (I/R*dR/dI)
  (m_excess = 0.8)       Magnitude of unexplained (excess) noise
  (R0 = 1.1)             Operating point resistance R0 [mOhm]
  (I0 = 72.5)            Current [muA]
  (Tb = 55)              Heat sink/bath temperature Tb [mK]
  (RL = 0.0)             Shunt/load resistor value RL [mOhm]
  (Rparasitic = 0.)      Parasitic resistor value Rparasitic [mOhm]
  (TTR = 4.11)           Transformer Turns Ratio
  (Lin = 238.)           Circuit inductance [nH]
  (Lfilter = 2.)         Filter inductance [muH]
  (V0 = -1.)             Effective voltage bias [muV]
  (thermalBias = n)      Calculate I0 and V0 from thermal power balance?
  (Pload = 0.0)          Residual optical load power [pW]
  (bias = 15)            Bias percentage of normal resistance in the transition
  (imin = -1e-8)         TES current corresponding to 0 ADU [A]
  (imax = 5e-5)          TES current corresponding to 65534 ADU [A]
  (simnoise = y)         Simulate noise?
  (stochastic_integrator = n)  Use the stochastic integrator? (default no)
  (twofluid = n)         Option to use the 2 fluid model of RTI transition (default no)
  (frame_hit = n)        Option to use frame hits (default no). Requires time of event and file name
  (frame_hit_time = 0.)  Time of frame event (s)
  (frame_hit_file = none)  File name of frame hit model
  triggertype = stream   Trigger type
  (triggersize = 1024)   Size of a trigger
  (prebuffer = 128)     Size of the prebuffer
  (propertiesonly = n)  Display properties of TES and exit without calculation?
  (Seed = 0)            Seed for the noise RNG (0 to use system time)
  (progressbar = y)     Display progress bar?
  (clobber = y)         Overwrite output files?
  (doCrosstalk = y)     Simulate Crosstalk (yes/no)?
  (readoutMode = total)  Readout mode for output current ['total': Absolute value, 'I': I-channel, 'Q':Q-channel]

```

Configuration control

Solution to large number of parameter problem:

self documentation \implies store all parameters in FITS files output by `tessim`: can reload exact pixel configuration from any stream produced by `tessim`:

First run `tessim` with `propertiesonly=yes`:

```
tessim PixType=LPA Ce=0.26 Gb=280 ... propertiesonly=yes
      ... Streamfile=testpixel.fits
```

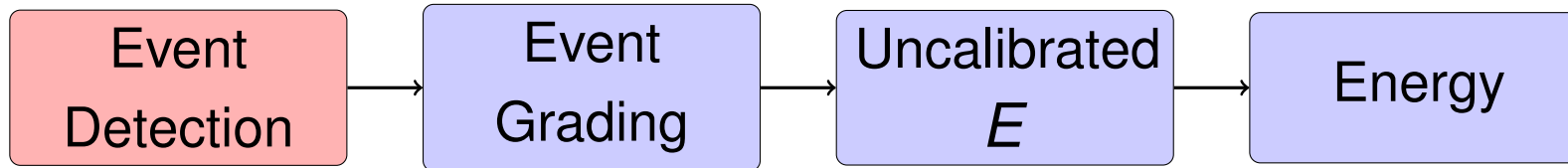
Later run with

```
tessim PixType=file:testpixel.fits[LPA]
      Streamfile=simulation PixImpList=impact.fits
```

where ... [LPA]: FITS selection syntax on FITS HDUNAME keyword.
impact.fits

: FITS impact file with TIME and ENERGY columns.

Trigger



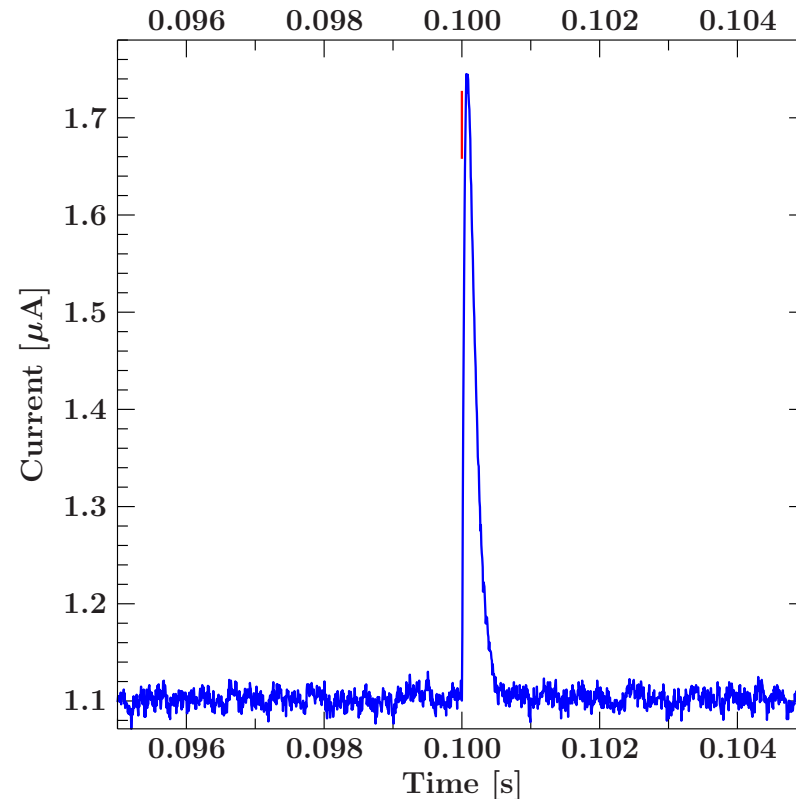
Iterative **Event Detection** (Triggering):

- Take derivative of TES stream

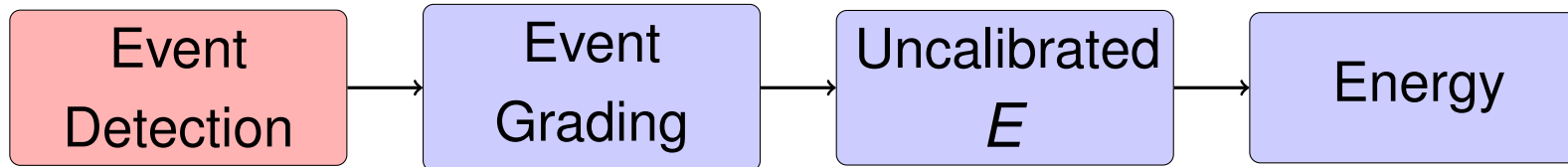
trigger=

- stream
- movavg:npts:threshold:suppress
- diff:npts:threshold:suppress

- remove pulses on the go to find others



Trigger



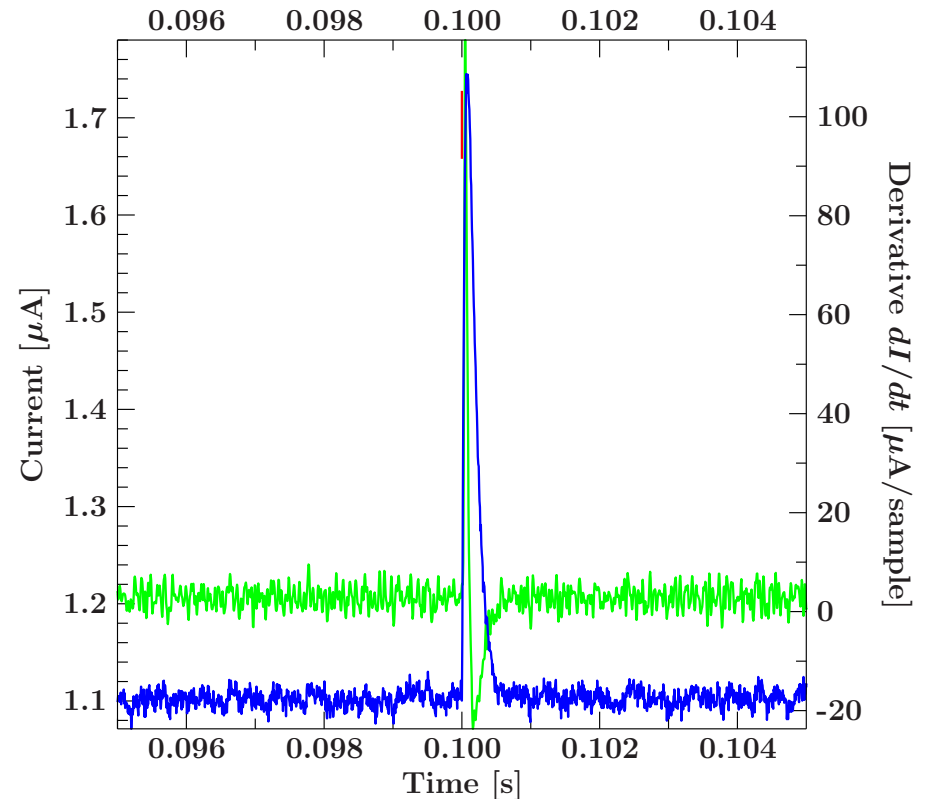
Iterative **Event Detection** (Triggering):

- Take derivative of TES stream

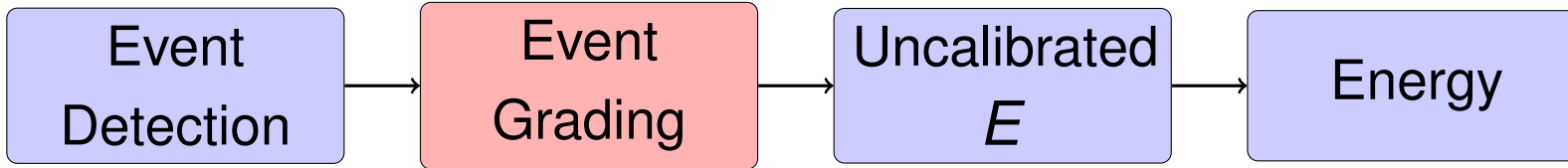
trigger=

- stream
- movavg:npts:threshold:suppress
- diff:npts:threshold:suppress

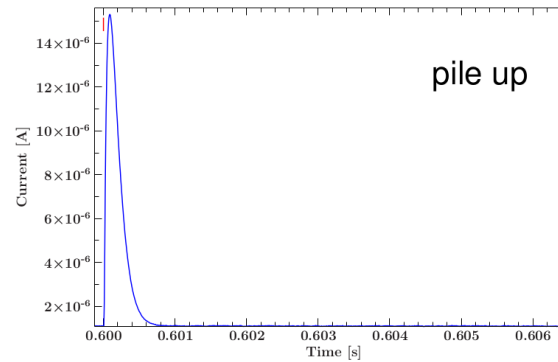
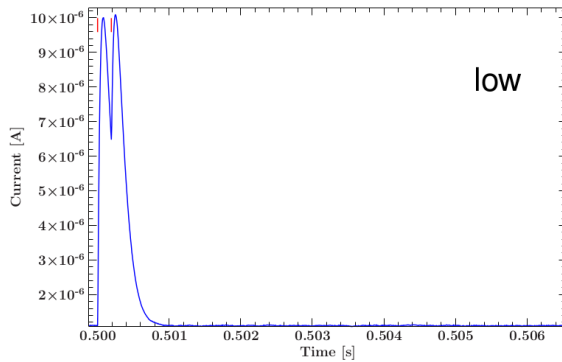
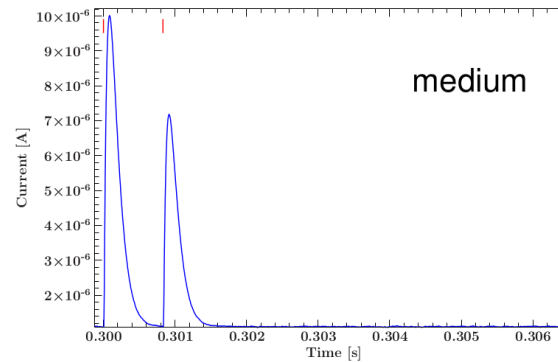
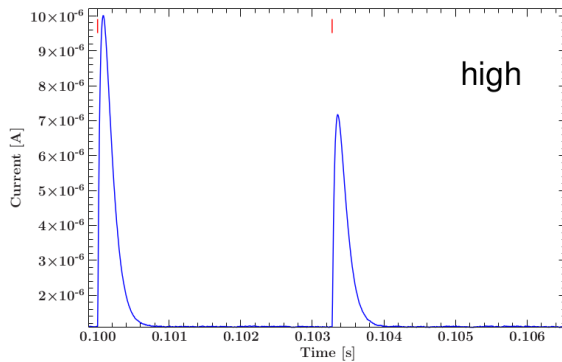
- remove pulses on the go to find others

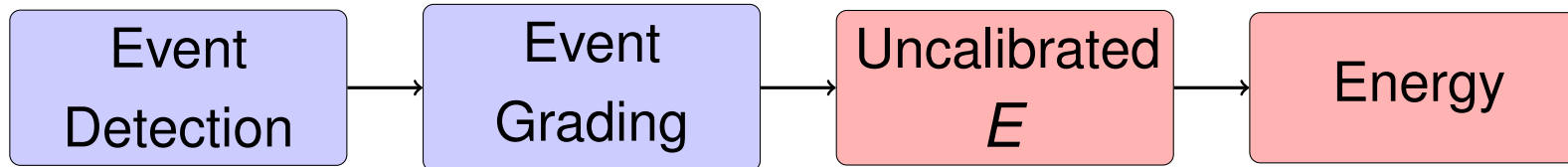


Trigger



Event Grading: Resolution depends on distance between different pulses.





Energy calculation: Use optimal filter (Szymkowiak et al., 1993):

$$E \propto \sum \frac{D(f)S^*(f)}{N(f)}$$

where

- $D(f)$: data spectrum,
- $S(f)$: template spectrum,
- $N(f)$: noise spectrum

Caveats:

- exact **degradation at higher energies not yet studied** for time reasons
- **reconstruction algorithms still in development** and under optimization, have done first studies using **principle component analysis** and **resistance space optimal filtering**